

Supporting Information

A dual-functional additive improves the performance of molecular bulk heterojunction photovoltaic cells

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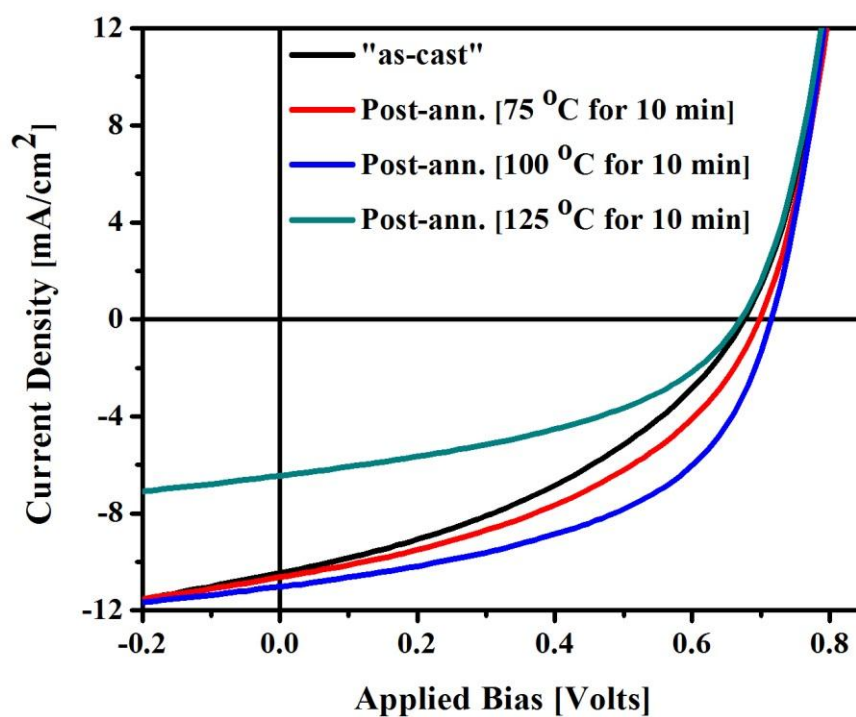


Figure S1. J – V characteristics of devices prepared without the additive and subjected to different post-annealing temperatures.

Table S1. Photovoltaic characteristics of devices prepared without the additive and subjected to different post-annealing temperatures.

Annealing Temp. [°C]	J_{sc} [mA/cm ²]	V_{oc} [V]	FF [%]	PCE [%]
“as-cast”	10.46	0.68	38.66	2.75
75°C	10.60	0.70	42.45	3.15
100 °C	10.20	0.71	48.33	3.50
125°C	6.45	0.67	43.04	1.86

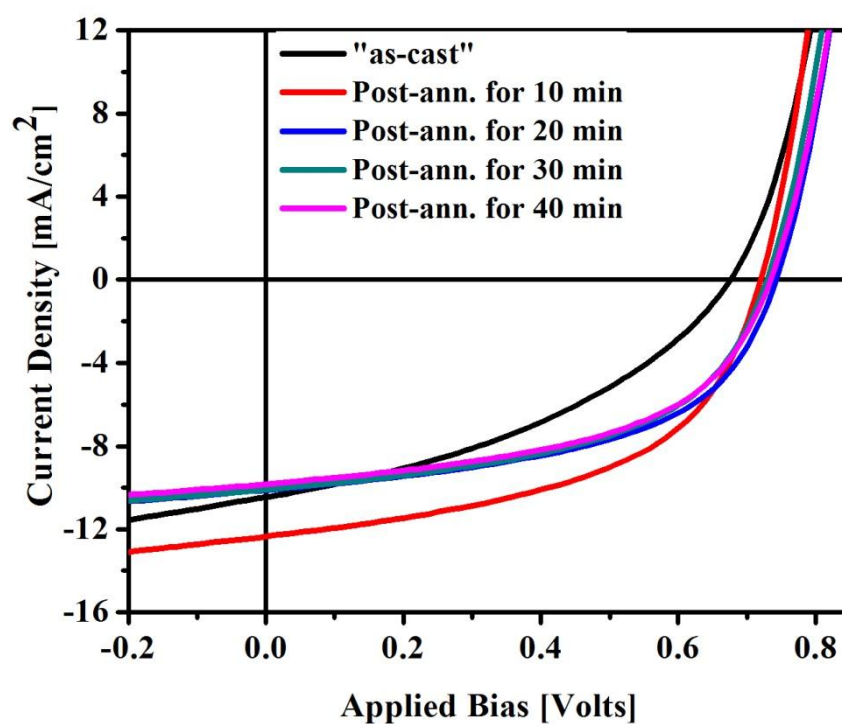


Figure S2. J – V characteristics of devices prepared with 0.1% of the additive CP3MS and post-annealing at 100 °C for different lengths of time.

Table S2. Photovoltaic characteristics of devices incorporating 0.1% of the additive that had been subjected to post-annealing at 100 °C for different lengths of time.

Annealing Time [min]	J_{sc} [mA/cm ²]	V_{oc} [V]	FF [%]	PCE [%]
“as-cast”	10.46	0.68	38.66	2.75
10	12.36	0.72	51.14	4.55
20	10.13	0.74	52.43	3.93
30	10.09	0.73	51.45	3.79
40	9.85	0.73	51.87	3.73

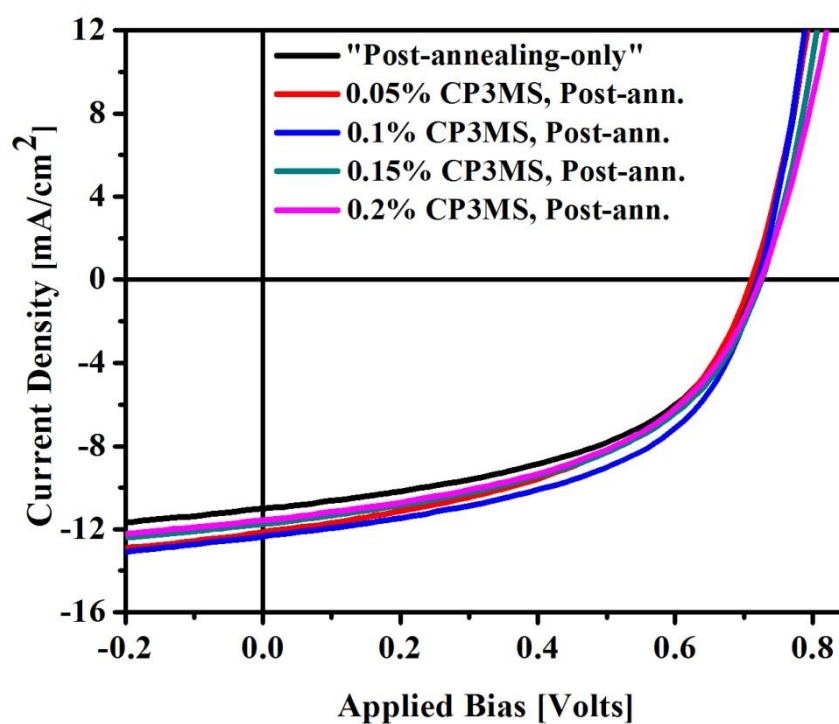


Figure S3. J - V characteristics of devices prepared with different CP3MS concentrations and post-annealing at 100 °C for 10 min.

Al-cathode smoothly removed



Post-annealed device



Device without Post annealing

**Active layer attached
with Al-cathode after
peel-off**

Figure S4. Digital camera images showing the effect of post-annealing treatment on the interface between the active layer and the metal cathode.

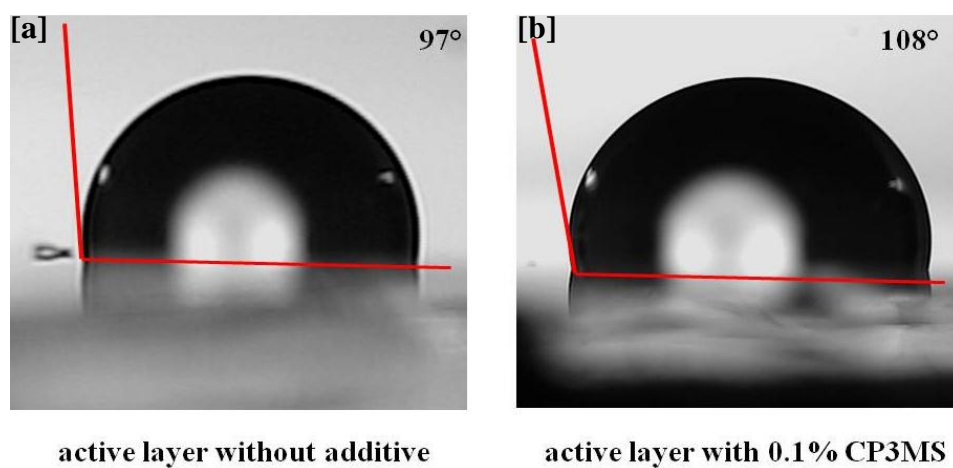
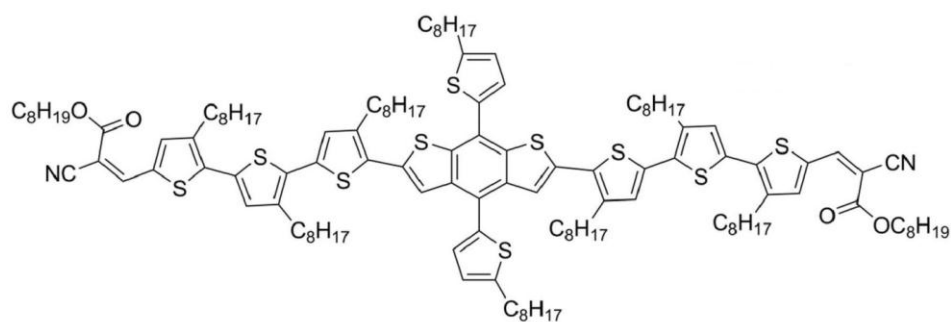


Figure S5. Images of contact angles of active layers without additive (a) and with 0.1% CP3MS additive (b)



Scheme S1. Chemical structure of benzodithiophene (BDT)-based molecule (TBDTCNR)

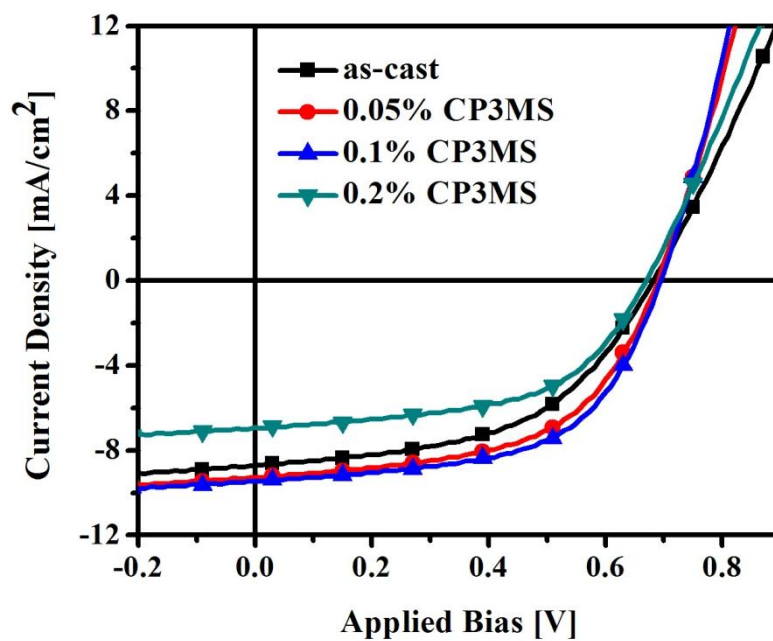


Figure S6: *J*–*V* characteristics of devices prepared with different CP3MS concentrations for benzodithiophene (BDT)-based molecule (TBDTCNR)

Table S3. Photovoltaic characteristics of devices prepared with different CP3MS concentrations for benzodithiophene (BDT)-based molecule (TBDTCNR).

Additive Conc. [%]	J_{sc} [mA/cm ²]	V_{oc} [V]	FF [%]	PCE [%]
“as-cast”	8.70	0.68	51.56	3.05
0.05% CP3MS	9.26	0.69	55.25	3.53
0.10% CP3MS	9.46	0.70	57.38	3.80
0.20% CP3MS	6.92	0.67	55.22	2.56